

Notice of References Cited	Application/Control No. 10/656,677	Applicant(s)/Patent Under Reexamination FAN ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0028380	03-2002	Tanjo et al.	429/209
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	I	US-			
	J	US-			
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	M	US-			

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